TOSHIBA 2SK2607

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE ( $\pi$ -MOSIII)

# 2 S K 2 6 0 7

HIGH SPEED, HIGH CURRENT SWITCHING APPLICATIONS CHOPPER REGULATOR, DC-DC CONVERTER AND MOTOR DRIVE **APPLICATIONS** 

Low Drain-Source ON Resistance :  $R_{DS(ON)} = 1.0 \Omega$  (Typ.)

High Forward Transfer Admittance :  $|Y_{fS}| = 7.0 \,\mathrm{S}$  (Typ.)

Low Leakage Current :  $I_{DSS} = 100 \,\mu\text{A}$  (Max.) ( $V_{DS} = 640 \,\text{V}$ )

:  $V_{th} = 2.0 \sim 4.0 \text{ V}$ Enhancement-Mode

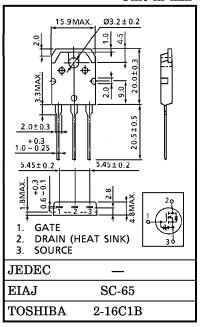
 $(V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA})$ 

### MAXIMUM RATINGS (Ta = 25°C)

CHARACTERIST	SYMBOL	RATING	UNIT		
Drain-Source Voltage	$ m V_{DSS}$	800	V		
Drain-Gate Voltage (RGS	$v_{ m DGR}$	800	V		
Gate-Source Voltage	$v_{GSS}$	±30	V		
Drain Current	DC	$I_{\mathbf{D}}$	9	A	
	Pulse	$I_{\mathrm{DP}}$	27		
Drain Power Dissipation	$P_{\mathbf{D}}$	150	W		
Single Pulse Avalanche	EAS	E <sub>AS</sub> 778			
Avalanche Current	$I_{AS}$	9	A		
Repetitive Avalanche En	$\mathrm{E}_{\mathrm{AR}}$	15	mJ		
Channel Temperature	$\mathrm{T_{ch}}$	150	°C		
Storage Temperature Ran	$\mathrm{T_{stg}}$	-55~150	°C		

### INDUSTRIAL APPLICATIONS

Unit in mm



Weight: 4.6 g

### THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Case	R <sub>th (ch-c)</sub>	0.833	°C/W
Thermal Resistance, Channel to Ambient	R <sub>th (ch-a)</sub>	50	°C/W

\* Repetitive rating; Pulse Width Limited by Max. junction temperature.

\*\*  $V_{DD} = 90 \text{ V}, T_{ch} = 25^{\circ}\text{C}$  (initial),  $L = 17.4 \text{ mH}, R_{G} = 25 \Omega, I_{AR} = 9 \text{ A}$ 

This transistor is an electrostatic sensitive device. Please handle with caution.

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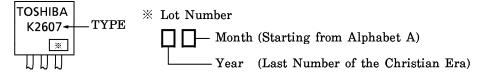
# ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		$I_{ m GSS}$	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	$\mu$ A
Gate-Source Breakdown Voltage		V (BR) GSS	$I_{G} = \pm 10 \mu\text{A},  V_{DS} = 0  \text{V}$	±30	_	_	V
Drain Cut-of	f Current	$I_{ m DSS}$	$V_{DS} = 640 \text{ V}, \ V_{GS} = 0 \text{ V}$	_	_	100	$\mu$ <b>A</b>
Drain-Source Breakdown Voltage		V (BR) DSS	$I_D = 10 \text{ mA}, \text{ V}_{GS} = 0 \text{ V}$	800	_	_	V
Gate Thresh	old Voltage	$V_{ m th}$	$V_{\mathrm{DS}} = 10  \mathrm{V}, \; \mathrm{I_D} = 1  \mathrm{mA}$	2.0	_	4.0	V
Drain-Source	ON Resistance	R <sub>DS</sub> (ON)	$V_{GS} = 10 \text{ V}, I_{D} = 4 \text{ A}$		1.0	1.2	Ω
Forward Tra Admittance	nsfer	Y <sub>fs</sub>	$V_{ m DS} = 15   m V,  I_{ m D} = 4   m A$	3.0	7.0	_	S
Input Capacitance		$\mathrm{c}_{\mathrm{iss}}$		_	2160	_	
Reverse Transfer Capacitance		C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, $ f = 1 MHz	_	45	_	pF
Output Capacitance		Coss		_	200	_	
Switching Time	Rise Time	t <sub>r</sub>	$V_{GS} \stackrel{10 \text{ V}}{_{0 \text{ V}}} \stackrel{I_{D} = 4 \text{ A}}{\underset{\text{FL} = 100 \Omega}{\text{Vout}}} $ $V_{DD} = 400 \text{ V}$ $V_{IN} : t_{r}, t_{f} < 5 \text{ ns},$ $Duty \le 1\%, t_{w} = 10 \mu\text{s}$	_	25	_	
	Turn-on Time	t <sub>on</sub>		_	60	_	ns
	Fall Time	$t_f$		_	25	_	
	Turn-off Time	t <sub>off</sub>		_	110	_	
Total Gate Charge (Gate- Source Plus Gate-Drain)		$\mathbf{Q}_{\mathbf{g}}$	$V_{DD} = 400 \text{ V}, V_{GS} = 10 \text{ V},$	_	68	_	nC
Gate-Source Charge		$\mathbf{Q}_{\mathbf{g}\mathbf{s}}$	$I_D = 9 A$	_	38	_	
Gate-Drain ("Miller") Charge		$\mathbf{Q}_{\mathbf{gd}}$			30	_	

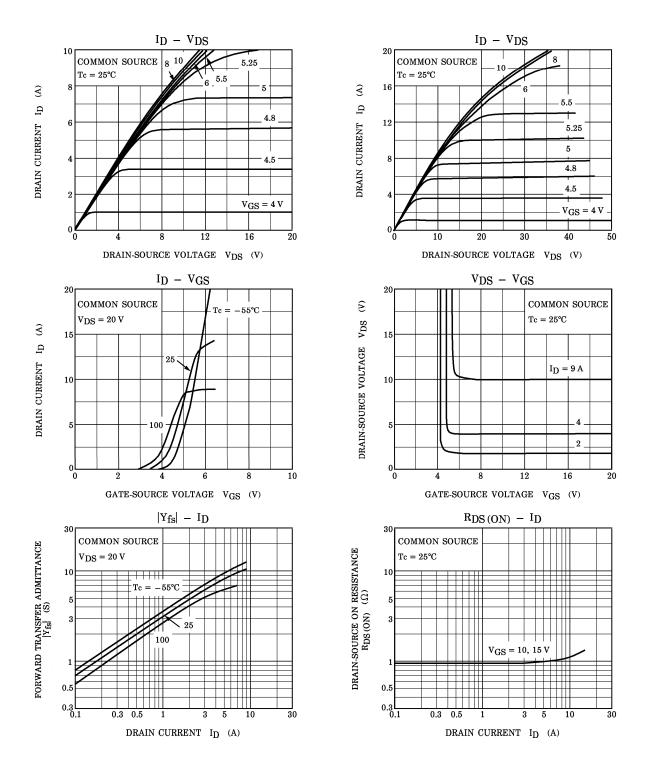
# SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

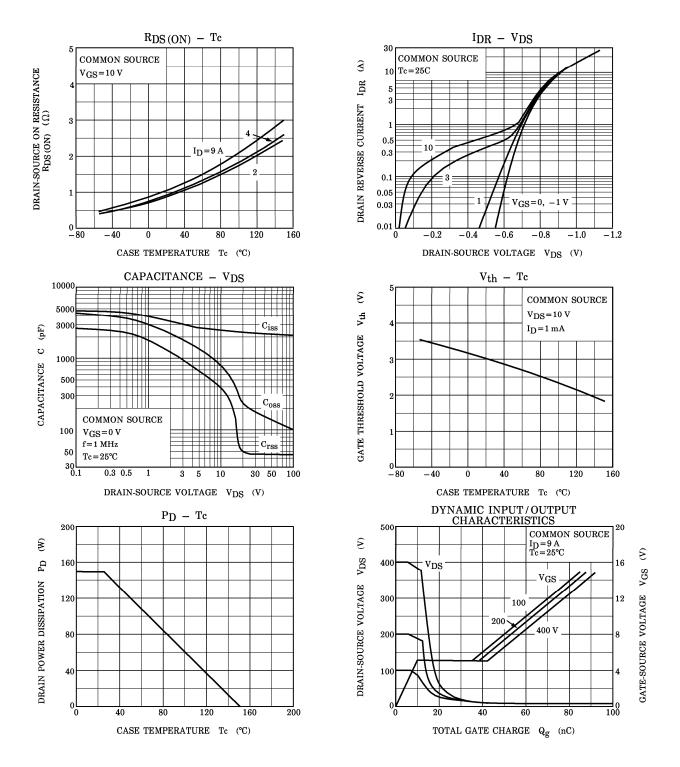
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	$I_{ m DR}$	_	_	_	9	A
Pulse Drain Reverse Current	${ m I}_{ m DRP}$	_	_	_	27	Α
Diode Forward Voltage	$v_{ m DSF}$	$I_{DR} = 9 A, V_{GS} = 0 V$	_	_	-1.9	V
Reverse Recovery Time	$t_{rr}$	$I_{DR} = 9 A$ , $V_{GS} = 0 V$		1000	_	ns
Reverse Recovery Charge	$Q_{rr}$	$dI_{DR}/dt = 100 A/\mu s$	_	12	_	$\mu$ C

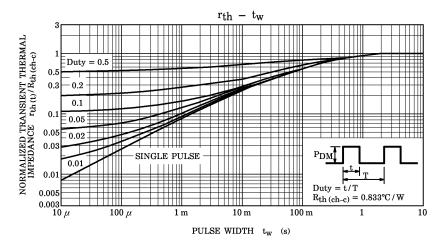
# **MARKING**

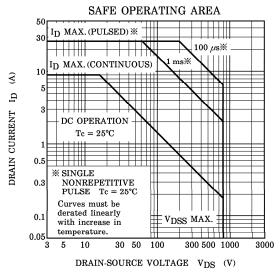


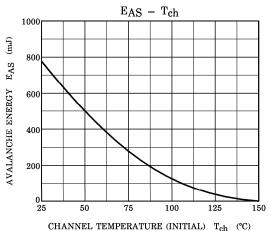
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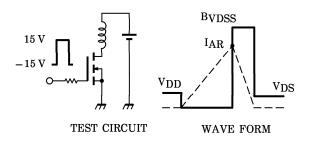












$$\begin{aligned} & \text{Peak I}_{AR} = 9 \text{ A, R}_{G} = 25 \; \Omega \\ & \text{V}_{DD} = 90 \; \text{V, L} = 17.4 \, \text{mH} \end{aligned} \quad \\ & \text{E}_{AS} = \frac{1}{2} \cdot \text{L} \cdot \text{I}^{2} \cdot \left( \; \frac{\text{BVDSS}}{\text{BVDSS} - \text{V}_{DD}} \right) \end{aligned}$$